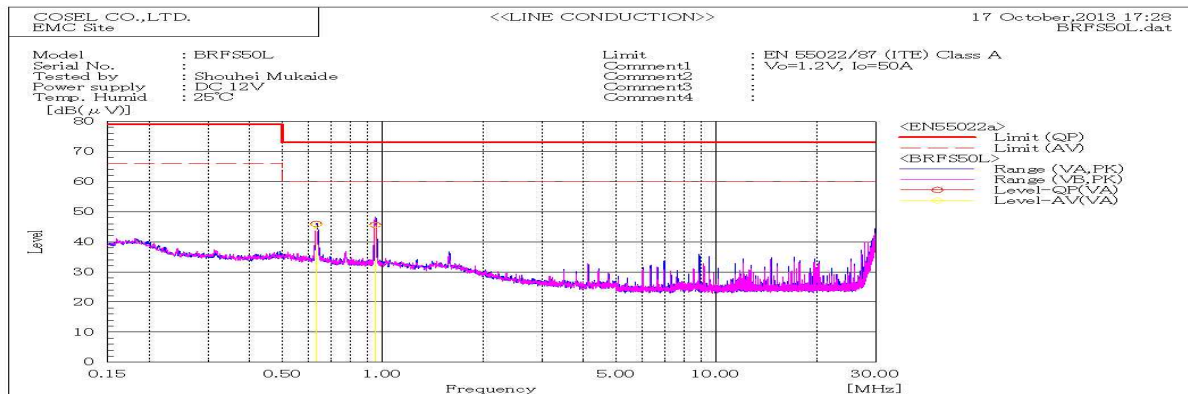
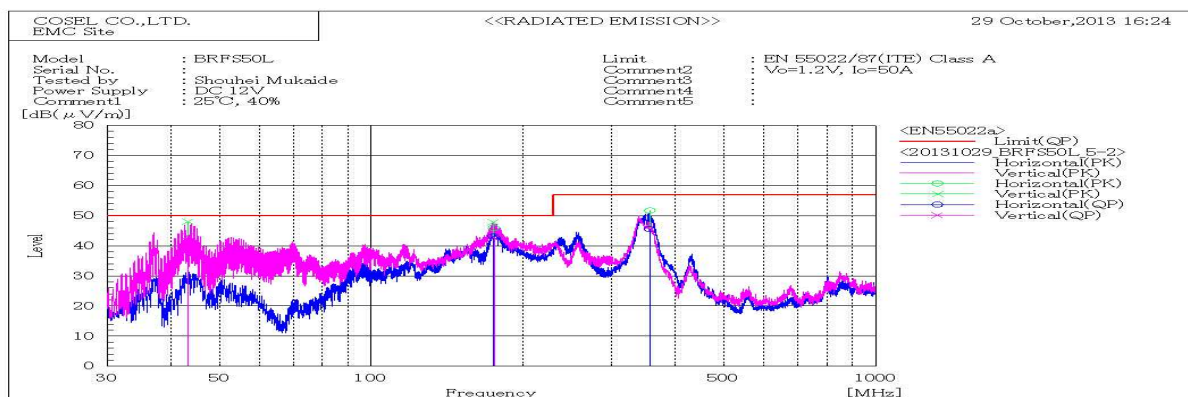


DATA SHEET

Model	BRFS50L	Date	29-Oct-13
Test	EMI Line conduction & Radiated emission	Temp.	25 degreeC
		Humid.	40 %RH
		Tested by	S.Mukaide



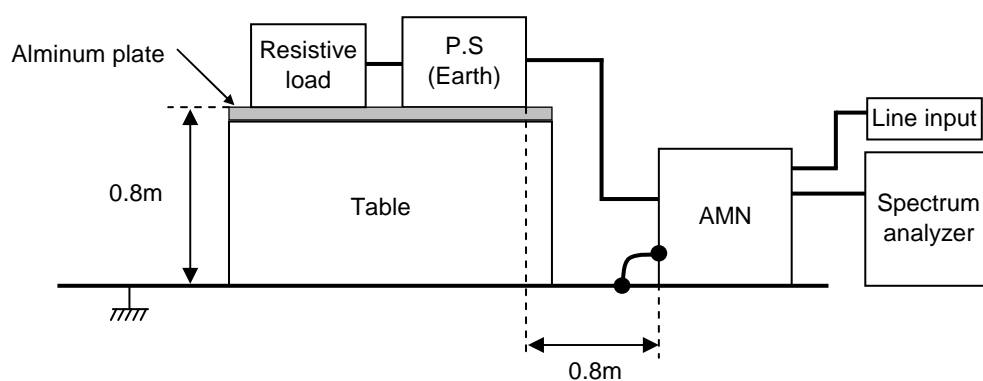
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.95115	VA	25.6	25.4	20.1	45.7	45.5	73	60	27.3	14.5	Pass
0.63317	VA	25.9	25.6	20	45.9	45.6	73	60	27.1	14.4	Pass



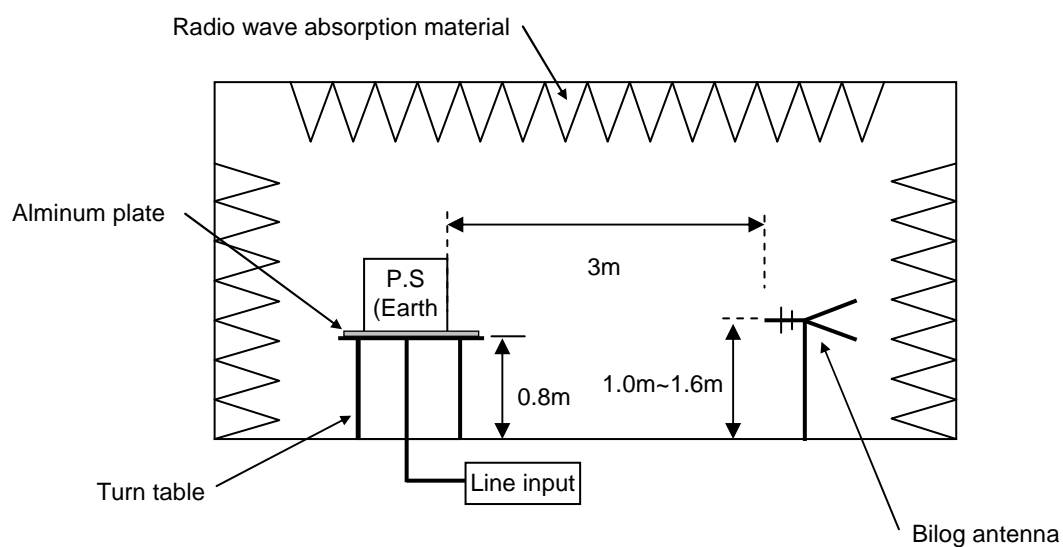
Frequency MHz	Polarization	Stability	Reading	Space Loss dB	Level	Limit	Margin dB	Pass/ Fail	Height cm	Angle deg
			dB(uV)		dB(mW)	dB(mW)				
43.283	V	Stable	60.6	-17.4	43.2	50	6.8	Pass	101	7
175.431	V	Stable	58.9	-16.2	42.7	50	7.3	Pass	159	341
174.512	H	Stable	65.4	-22.3	43.1	50	6.9	Pass	151	84
356.403	H	Stable	58.7	-13.1	45.6	57	11.4	Pass	104	28

DATA SHEET		Date	29-Oct-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mukaide

1. Line conduction



2. Radiated emission

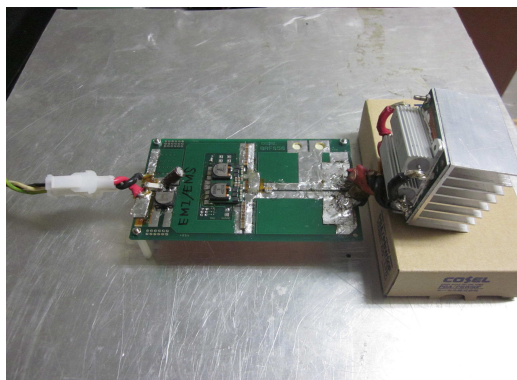


Conditions

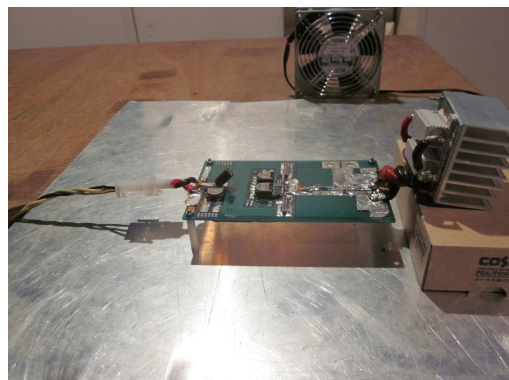
Test : EMI
Model Name : BRFS50L

○Photographs of Test Set-Up

LINE CONDUCTION

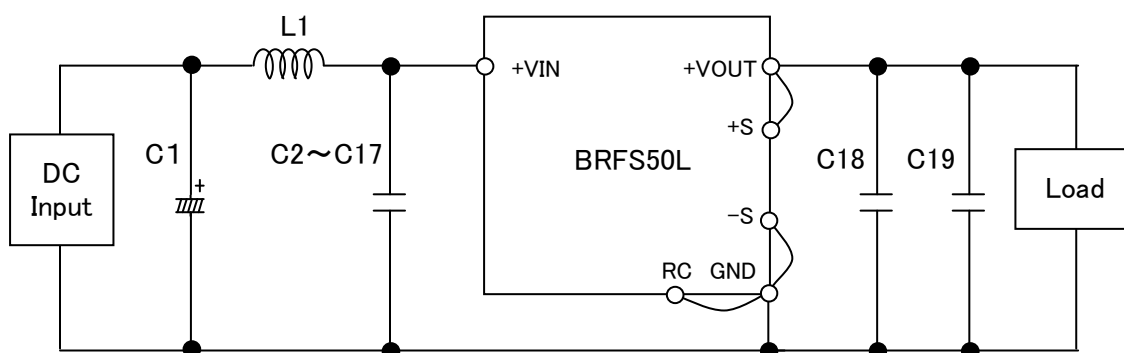


RADIATED EMISSION



○Testing circuitry

○Test Circuit



C1	: 25V	220 μ F	Electrolytic capacitor
C2~C17	: 16V	22 μ F	Ceramic capacitor
C18 ,C19	: 6.3V	100 μ F	Ceramic capacitor
L1	: 0.3 μ H	ETQP2H0R3BFA (Panasonic Electronics Devices)	